

Universidade do Minho Escola de Ciências

Dielectric Properties

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Outline

Main Objective: Fit a model to experimental data and assess its validity.

- 1. Brief introduction to key concepts;
- 2. Fitting the model in study to portions of the experimental data;
- 3. Performing the fit across the whole domain for both data sets individually;
- 4. Introducing new elements in the model;
- 5. Repeating the individual fits and computing a global fit to both data sets simultaneously;
- 6. Concluding remarks.

Introduction...

Physics Case: Lithium Niobate

- It's a displacement ferroelectric with very usefull features;
- It shows great promise for devices such as:
 - Wave-guide optical devices;
 - SAW devices for chemical detectors;
 - FRAM and RRAM units;



• ...

Physics Case: Experimental Method

- A flat-faced capacitor is made using the dielectic sample;
- Capacitive response is related to dipoles reorientation mobility → huge amount of

information:

- a) structure of matter;
- b) ion displacement;
- c) valence cloud distortion;
- d) ...



Physics Case: Experimental Method

- Different responses can be studied with a wide range of frequencies;
- Dipolar polarization is studied up to a range of about 10¹⁰ Hz;
- Different preparation conditions may lead to different responses → BDS can act as a quality control;



Initial Steps



Error Sources

From the **experimental** procedure: 1%

Considering the error associated with the **area measurement**, the final error is about 10%.





The Data



Statistical Analysis

To test the validaty of a theoretical model, comparing it with experimental data is crutial.

Fitting models to experimental data is a key part of physics.

How can we measure the goodness of a fit?

Fitting...

The Data – Imaginary Part



Fitting Portions – Imaginary Part





 $= \frac{\sigma_{\rm DC}}{\epsilon_0 \omega}$

Fitting Portions – Imaginary Part





$$\epsilon'' = \operatorname{Im}\left[\frac{\Delta\epsilon}{\left(1 + (i\omega\tau)^{\beta}\right)^{\gamma}}\right] + \frac{\sigma_{\mathrm{DC}}}{\epsilon_{0}\omega^{s}}$$

	$ au_{HN}$ [s]	β	γ	$\sigma_{DC} \ [\Omega^{-1}m^{-1}]$	s	$\Delta \varepsilon$
	$7.4 imes 10^{-5}$	0.86	1.12	$2.0 imes 10^{-8}$	0.65	106
±	$0.6 imes 10^{-5}$	0.03	0.06	0.6×10^{-8}	0.05	4

- All the parameters present orders of magnitude close to the expected.
- $0 < \gamma \beta \leq 1$







$$\epsilon'' = \operatorname{Im}\left[\frac{\Delta\epsilon}{\left(1 + (i\omega\tau)^{\beta}\right)^{\gamma}}\right] + \frac{\sigma_{\mathrm{DC}}}{\epsilon_{0}\omega^{s}}$$

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Goodness of fit parameters:

$$\chi^2 = 100.56$$
 $\overline{\chi}^2 = 0.37$ p-value = 1.0

Individual Fit – Real Part



$$\epsilon' = \epsilon_{\infty} + \operatorname{Re}\left[\frac{\Delta\epsilon}{\left(1 + (i\omega\tau)^{\beta}\right)^{\gamma}}\right]$$

	$ au_{HN}$ [s]	β	γ	ε_∞	$\Delta \varepsilon$
	$8.0 imes 10^{-5}$	0.86	1.13	0.97	120
\pm	0.2×10^{-5}	0.02	0.03	0.01	3

- All the parameters presente orders of magnitude close to the expected.
- $0 < \gamma \beta \leq 1$
- Some diferences compared with the Im part;

Individual Fit – Real Part



Individual Fit – Real Part



$$\epsilon' = \epsilon_{\infty} + \operatorname{Re}\left[\frac{\Delta\epsilon}{\left(1 + (i\omega\tau)^{\beta}\right)^{\gamma}}\right]$$

	$ au_{HN}$ [s]	β	γ	ε_∞	$\Delta \varepsilon$
	$8.0 imes 10^{-5}$	0.86	1.13	0.97	120
\pm	0.2×10^{-5}	0.02	0.03	0.01	3

Goodness of fit parameters:

$$\chi^2 = 203.47$$
 $\overline{\chi}^2 = 0.75$ p-value = 0.95

Real Part – What to Improve



Systematic uncertainty dominates. How to reduce it?

- Improved image quality;
- Ultra thin film of a conducting metal (Au, Ag, Al...);
- Contactless measure;
- Electrode connected with spring mechanism;

With some improvements the systematic uncertainty could **be reduced to 5%**.

What's the effect of this?

Real Part – What to Improve



What's the effect of this?

The imaginary part stays equally good.

For the **real** part:

 $\chi^2 = 406.9$ $\overline{\chi}^2 = 1.49$ p-value < 0.05

The model is no longer adequate do describe the experimental data.

How could we improve the fit?

- High frequency region is well fitted;
- Low frequency has to increase;
- This resembles: 1/x

Correcting the Model...

Correcting the Model: Maxwell-Wagner

Inhomogeneous samples may lead to separation of charges.

This effect is especially noticeable for low frequencies.

The contribution to dielectric loss can therefore be orders of magnitude larger than other contributions.



New Model

For the **imaginary** part of the permitivity:



For the **real** part of the permitivity:



New Individual Fits



	$ au_{HN}$ [s]	β	γ	$a \ [rad \ s^{-1}]$	n	ε_∞	$\Delta \varepsilon$
	7.6×10^{-5}	0.89	1.10	1086	0.62	0.94	104
±	$0.3 imes 10^{-5}$	0.02	0.04	451	0.05	0.02	4



	$ au_{HN}$ [s]	β	γ	$\sigma_{DC} \left[\Omega^{-1} m^{-1} \right]$	s	$\Delta \varepsilon$
	7.4×10^{-5}	0.87	1.12	2.0×10^{-8}	0.66	108
\pm	$0.6 imes 10^{-5}$	0.03	0.06	$0.6 imes 10^{-8}$	0.05	4





$$\epsilon' = \epsilon_{\infty} + \operatorname{Re}\left[\frac{\Delta\epsilon}{(1+(i\omega\tau)^{\beta})^{\gamma}}\right] + \frac{a}{\omega^{n}}$$
$$\epsilon'' = \operatorname{Im}\left[\frac{\Delta\epsilon}{(1+(i\omega\tau)^{\beta})^{\gamma}}\right] + \frac{\sigma_{\mathrm{DC}}}{\epsilon_{0}\omega^{s}}$$

	$ au_{HN}$ [s]	eta	γ	$\sigma_{DC} \left[\Omega^{-1} m^{-1} \right]$	$a \ [rad \ s^{-1}]$	n	ε_{∞}	s	$\Delta \varepsilon$
,	7.4×10^{-5}	0.87	1.14	2.0×10^{-8}	1061	0.63	0.98	0.66	106
± (0.4×10^{-5}	0.02	0.04	0.4×10^{-8}	536	0.06	0.03	0.03	3

Goodness of fit parameters:

$$\chi^2 = 83.4$$
 $\overline{\chi}^2 = 0.31$ p-value = 1.0



105

 ω [rad s⁻¹]

10⁶

107

104

10³

	$ au_{HN}$ [s]	β	γ	$\sigma_{DC} \ [\Omega^{-1}m^{-1}]$	$a \ [rad \ s^{-1}]$	n	ε_{∞}	s	$\Delta \varepsilon$
\pm 0	7.4×10^{-5} 0.4×10^{-5}	$\begin{array}{c} 0.87\\ 0.02 \end{array}$	$\begin{array}{c} 1.14 \\ 0.04 \end{array}$	2.0×10^{-8} 0.4×10^{-8}	$\begin{array}{c} 1061 \\ 536 \end{array}$	$\begin{array}{c} 0.63 \\ 0.06 \end{array}$	$\begin{array}{c} 0.98 \\ 0.03 \end{array}$	$\begin{array}{c} 0.66 \\ 0.03 \end{array}$	$\frac{106}{3}$

$$\sigma_{DC} = (2.0 \pm 0.4) \times 10^{-8} \ [\Omega^{-1} m^{-1}]$$

$$a\varepsilon_0 = (0.9 \pm 0.4) \times 10^{-8} \ [\Omega^{-1}m^{-1}]$$

Goodness of fit parameters:

$$\chi^2 = 83.4$$
 $\overline{\chi}^2 = 0.31$ p-value = 1.0







































Overview

- An initial fit to portions of the data allowed us to confirm the order of magnitude;
- The individual fits showed a good agreement with the experimental data with 10% uncertainty;
- After reflecting about the experimental procedure a reduction to 5% on the uncertainty was considered;
- With 5% uncertainty the individual fit for $\epsilon'(\omega)$ did not describe the experimental data correctly;
- The Maxwell-Wagner effect was added to the initial model;
- The new model produced fits in total agreement with the experimental data.

Main conclusion: After the addition of the Maxwell-Wagner Effect the model correctly describes the physics in study even for 5% uncertainty.

Complementary Slides...

Laser Ablation

- It's a PVD technique;
- The sample is irradiated with a pulsed laser creating a plasm plume;
- The plasma componentes expand adiabatically to reach the substrate.



Advantages and Disavantages of Laser Ablation

Advantages

- Low heat transfer;
- Environmentally friendly;
- Cost effective;
- Low energy waste;

Disavantages

- Low deposition rates;
- Requires expensive and largedimension equipment;
- Requires great ammount of energy;

Advantages of Dielectric Spectroscopy

- Specialized staff isn't required to use this technique;
- It's relatively non-invasive (in terms of voltage used);
- A wide range of samples can be analized with this technique;
- It allows the use of conditions that can't be used in other analysis;

Disadvantages of Dielectric Spectroscopy

- Some samples have a low response that can't be detected by the equipment;
- The methods used to conect the electrodes to the sample may deteriorate the sample;
- Some interesting responses may be swamped by the response of less interesting componentes with higher intensity;

Benefits of a sputtered metal contact

- The contact area will be much more regular with the use of a mask;
- Better contact thickness and area controll;
- Uniform contact surface;
- Sample contamination is reduced when compared with silver paint contacts;